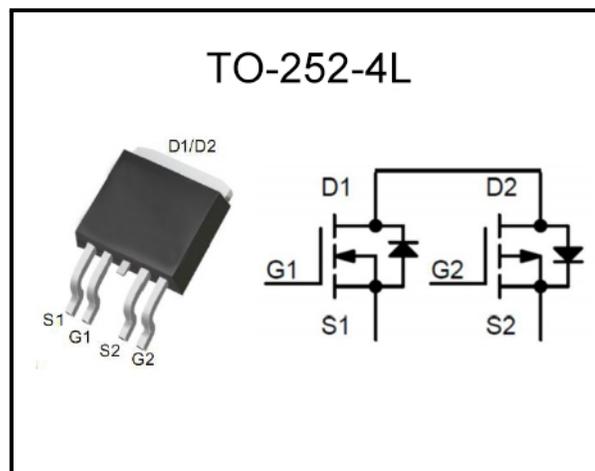


Features

- **N-Channel:**
- $V_{(BR)DSS}=30V$
- $I_D=30A$
- $R_{DS(ON)}@V_{GS}=\pm 10V, TYP=10m\Omega$
- $R_{DS(ON)}@V_{GS}=\pm 4.5V, TYP=13m\Omega$
- **P-Channel:**
- $V_{(BR)DSS}=-30V$
- $I_D=-22A$
- $R_{DS(ON)}@V_{GS}=\pm 10V, TYP=24m\Omega$
- $R_{DS(ON)}@V_{GS}=\pm 4.5V, TYP=40m\Omega$
- Enhancement mode
- Very low on-resistance
- Fast Switching
- Pb-free lead plating; RoHS compliant

Package



Ordering Information

Part Number	Storage Temperature	package	Devices Per Reel
BMI403NP1136	-55°C to +150°C	TO-252-4L	2500pcs/Reel

Absolute Maximum Ratings ($T_J=25^\circ C$ unless otherwise specified)

Symbol	Parameter	NMOS	PMOS	Units	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	30	-30	V	
V_{GS}	Gate - Source Voltage	± 20	± 20	V	
I_S	Diode Continuous Forward Current	30	-22	A	
T_J, T_{stg}	Storage and operating temperature range	-55 to +150		°C	
Mounted on Large Heat Sink					
I_{DM}	Pulse Drain Current Tested ⁽²⁾	$T_C=25^\circ C$	120	-88	A
I_D	Continuous Drain Current	$T_C=25^\circ C$	30	-22	A
		$T_C=100^\circ C$	19	-14	
P_D	Power dissipation for Dual Operation	$T_C=25^\circ C$	25	W	
$R_{\theta JC}$	Thermal Resistance From Junction to Case		6	°C/W	
$R_{\theta JA}$	Thermal Resistance from Junction to Ambient		45	°C/W	
Drain-Source Avalanche Ratings					
E_{AS}	Avalanche Energy, Single Pulsed		56 ⁽³⁾	72 ⁽⁴⁾	mJ



N-Channel Electrical Characteristics (T_J=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Units
Static Electrical Characteristics						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D =250uA	30	–	–	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30V, V _{GS} =0V	–	–	1	uA
		V _{DS} = 30V, V _{GS} =0V, T _J =125°C	–	–	100	
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} =0V	–	–	±100	nA
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D =250uA	1.0	1.6	2.5	V
Static Drain-source On Resistance ⁽²⁾	R _{DS(ON)}	V _{GS} =10V, I _D =8A	–	10	13	mΩ
		V _{GS} =4.5V, I _D =6A	–	14	18	
Dynamic Electrical Characteristics						
Input capacitance	C _{iss}	V _{DS} =25V,	–	880	–	pF
Output capacitance	C _{oss}	V _{GS} =0V,	–	110	–	
Reverse transfer capacitance	C _{rss}	f = 1MHz	–	95	–	
Gate to Drain Charge	Q _g	V _{DS} =15V,	–	18	–	nC
Gate to Source Charge	Q _{gs}	V _{GS} =10V,	–	3.8	–	
Gate to Drain Charge	Q _{gd}	I _D =10A	–	4.5	–	
Switching Characteristics						
Turn-on delay time	T _{d(on)}	V _{DD} =15V,	–	7	–	nS
Turn-on Rise time	T _r	V _{GS} =10V,	–	14	–	
Turn -Off Delay Time	T _{d(off)}	R _G =3.3Ω,	–	22	–	
Turn -Off Fall time	T _f	I _D =3.5A	–	8	–	
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _{SD} =10A	–	0.83	1.2	V
Reverse Recovery Time	T _{rr}	I _{SD} =10A, V _{GS} =0V	–	13	–	nS
Reverse Recovery Charge	Q _{rr}	di/dt=-500A/μs, T _J =25°C	–	11	–	nC



P-Channel Electrical Characteristics (T_J=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Units
Static Electrical Characteristics						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-30	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -30V, V _{GS} = 0V	-	-	-1	μA
		V _{DS} = -30V, V _{GS} = 0V, T _J = 125°C	-	-	-100	
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = -250μA	-1.0	-1.5	-2.5	V
Static Drain-source On Resistance ⁽²⁾	R _{DS(ON)}	V _{GS} = -10V, I _D = -6A	-	24	30	mΩ
		V _{GS} = -4.5V, I _D = -5A	-	40	50	
Dynamic Electrical Characteristics						
Input capacitance	C _{iss}	V _{DS} = -25V,	-	950	-	pF
Output capacitance	C _{oss}	V _{GS} = 0V,	-	115	-	
Reverse transfer capacitance	C _{rss}	f = 1MHz	-	105	-	
Gate to Drain Charge	Q _g	V _{DS} = -15V,	-	18	-	nC
Gate to Source Charge	Q _{gs}	V _{GS} = -10V,	-	5	-	
Gate to Drain Charge	Q _{gd}	I _D = -5A	-	4.2	-	
Switching Characteristics						
Turn-on delay time	T _{d(on)}	V _{DD} = -15V,	-	11	-	nS
Turn-on Rise time	T _r	V _{GS} = -10V,	-	39	-	
Turn -Off Delay Time	T _{d(off)}	R _G = 3.3Ω,	-	26	-	
Turn -Off Fall time	T _f	I _D = -5A	-	30	-	
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} = 0V, I _{SD} = -6A	-	-0.85	-1.2	V
Reverse Recovery Time	T _{rr}	I _{SD} = -5A, V _{GS} = 0V	-	31	-	nS
Reverse Recovery Charge	Q _{rr}	di/dt = 2000A/μs, T _J = 25°C	-	19	-	nC

Notes:

- (1) Repetitive rating; pulse width limited by max. junction temperature.
- (2) Pulse Test: Pulse Width ≤ 300μs, duty cycle ≤ 2%.
- (3) Limited by T_{J(MAX)}, starting T_J = 25°C, L = 0.5mH, R_G = 25Ω, I_{AS} = 15A, V_{GS} = 10V. Part not recommended for use above this value
- (4) Limited by T_{J(MAX)}, starting T_J = 25°C, L = 0.5mH, R_G = 25Ω, I_{AS} = -17A, V_{GS} = -10V. Part not recommended for use above this value



N-Channel Typical Characteristics

Figure 1: Typical Output Characteristics

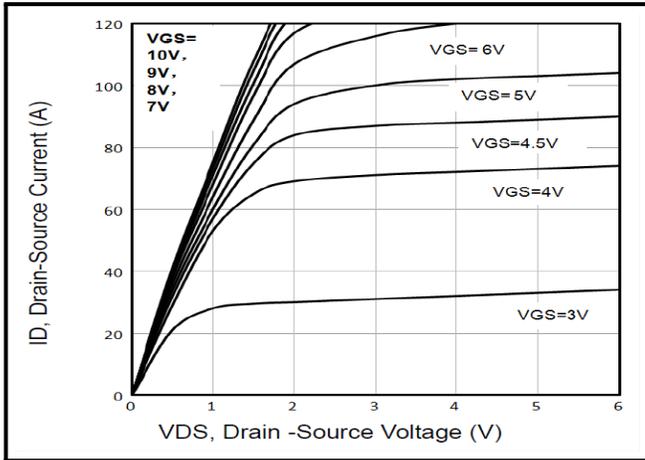


Figure 2: $V_{GS(TH)}$ Gate -Source Voltage Vs. T_j

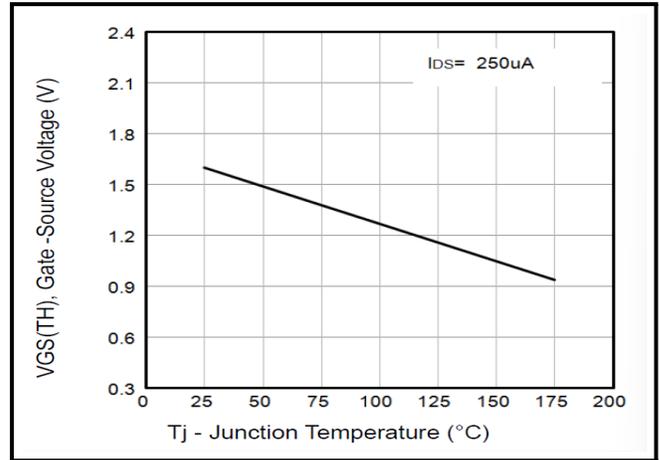


Figure 3: Typical Transfer Characteristics

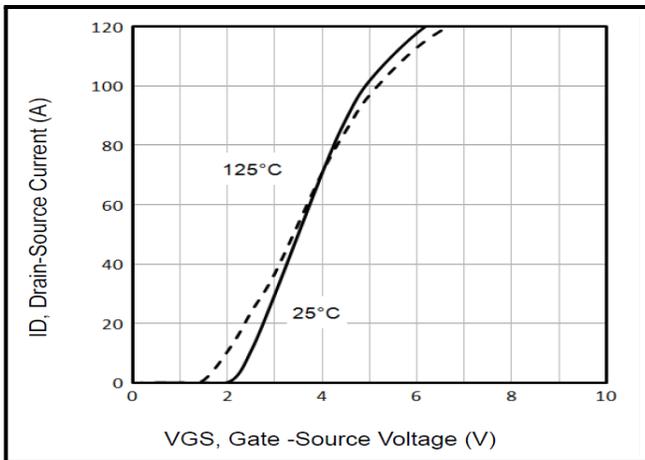


Figure 4: Normalized On-Resistance Vs. T_j

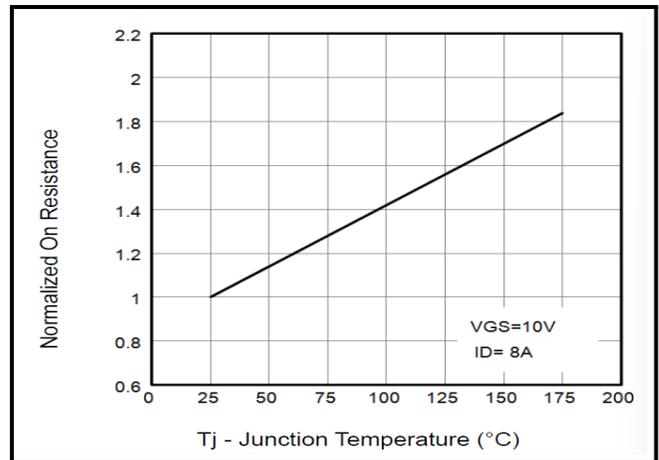


Figure 5: Typical Source-Drain Diode Forward Voltage

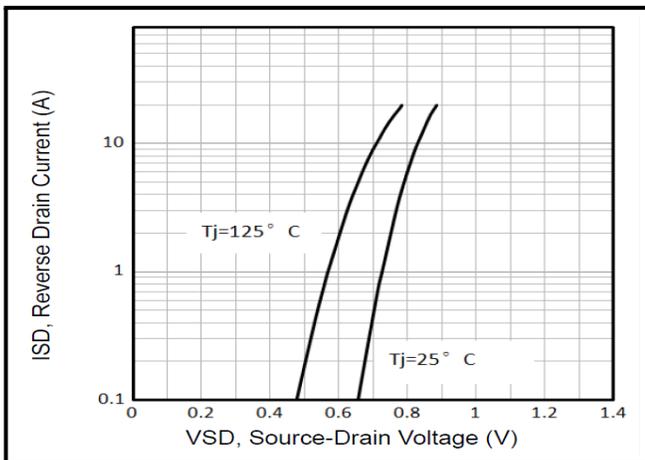
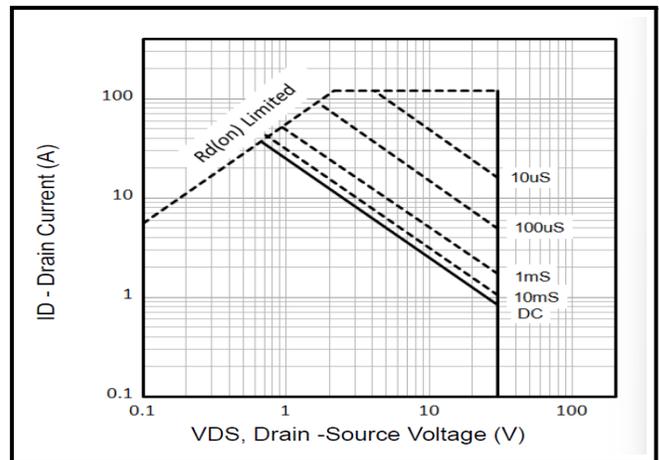


Figure 6: Maximum Safe Operating Area



N-Channel Typical Characteristics

Figure 7: Typical Capacitance Vs. Drain-Source Voltage

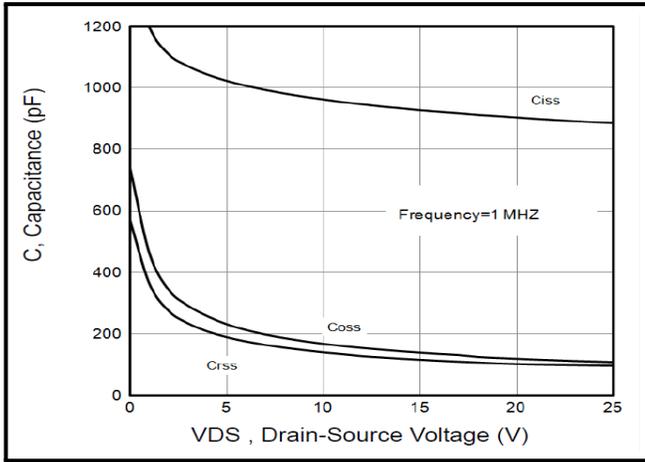


Figure 8: Typical Gate Charge Vs. Gate-Source Voltage

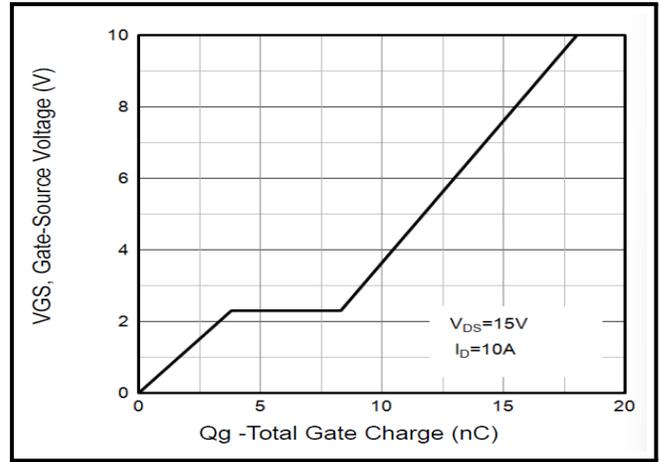


Figure 9: Normalized Maximum Transient Thermal Impedance

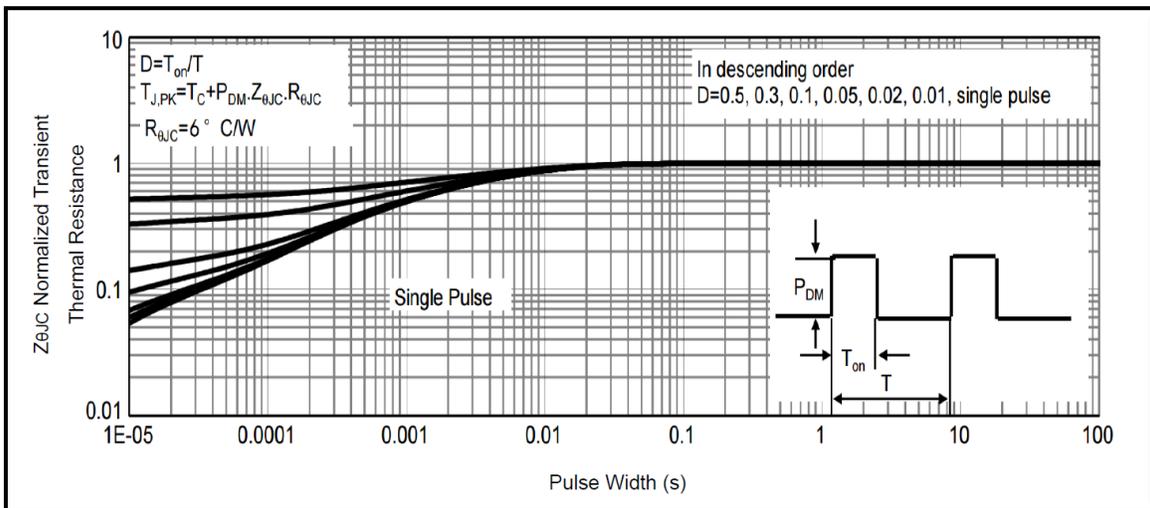


Figure 10: Unclamped Inductive Test Circuit and wave-

forms

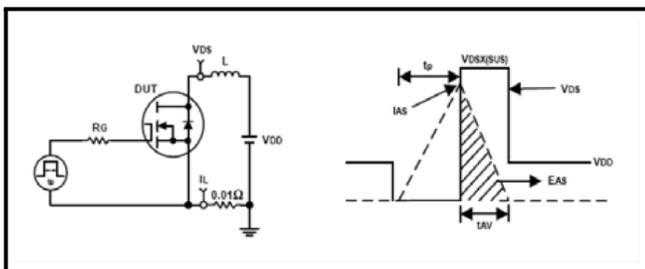
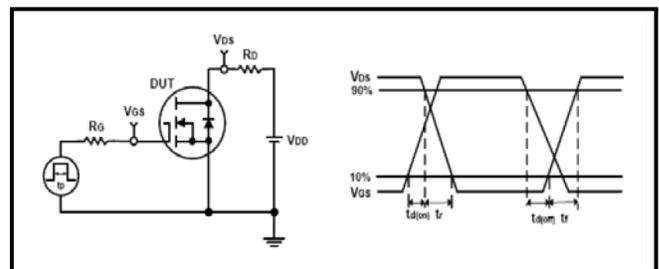


Figure 11: Switching Time Test Circuit and wave-



P-Channel Typical Characteristics

Figure 12: Typical Output Characteristics

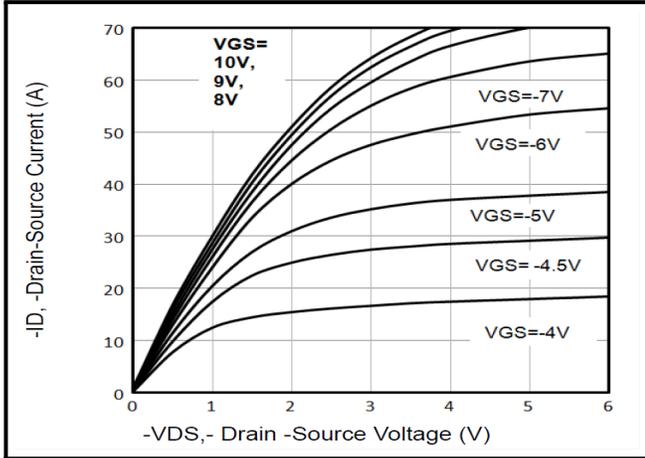


Figure 13: VGS(TH) Gate -Source Voltage Vs. Tj

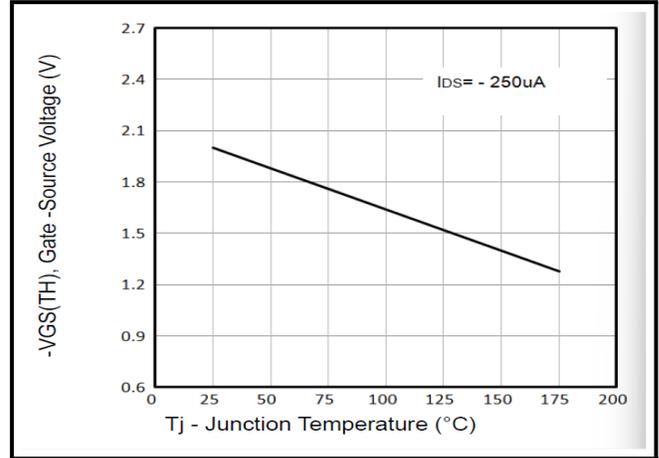


Figure 14: Typical Transfer Characteristics

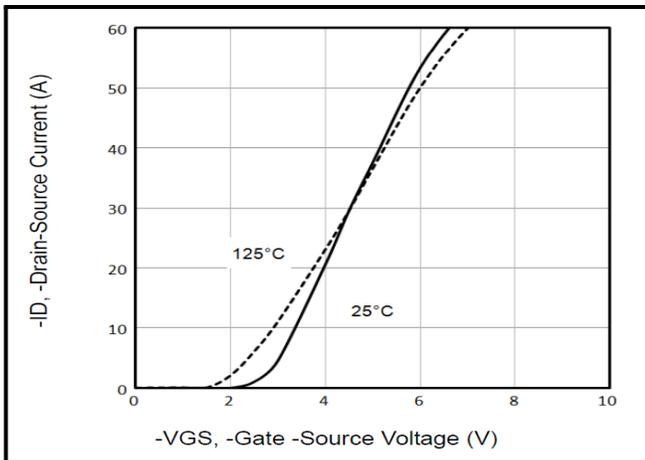


Figure 15: Normalized On-Resistance Vs. Tj

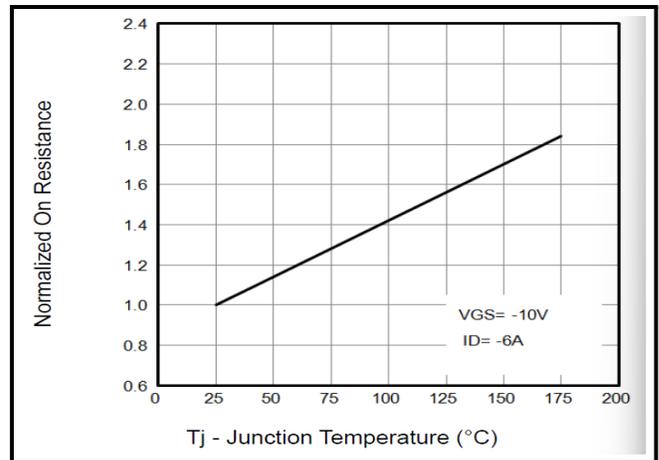


Figure 16: Typical Source-Drain Diode Forward Voltage

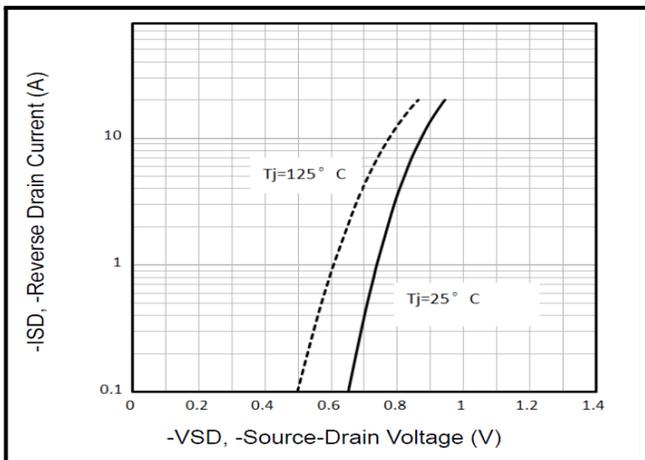
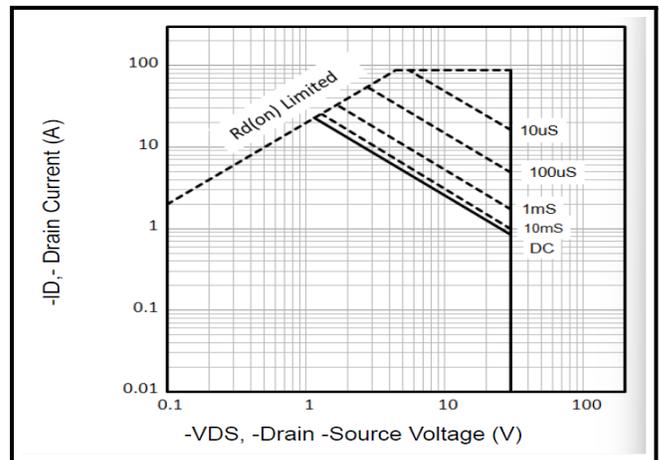


Figure 17: Maximum Safe Operating Area



P-Channel Typical Characteristics

Figure 18: Typical Capacitance Vs. Drain-Source Voltage

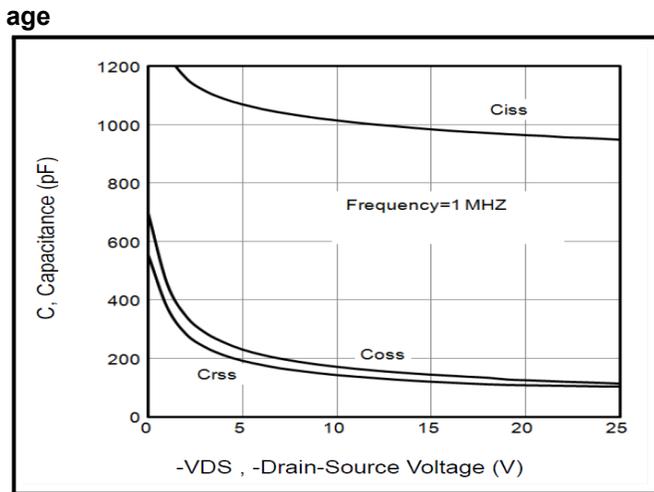


Figure 19: Typical Gate Charge Vs. Gate-Source Voltage

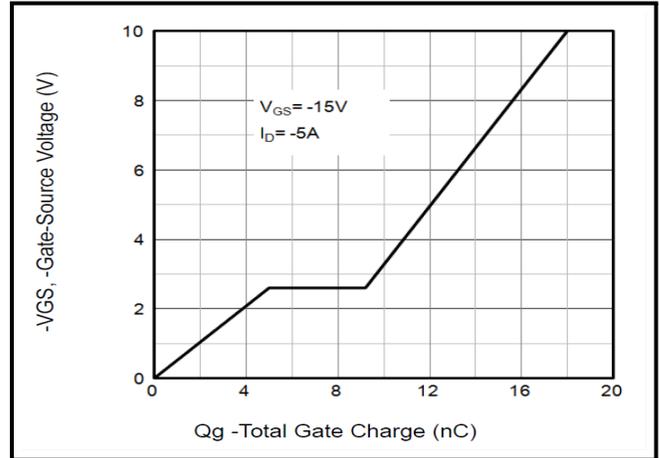


Figure 20: Normalized Maximum Transient Thermal Impedance

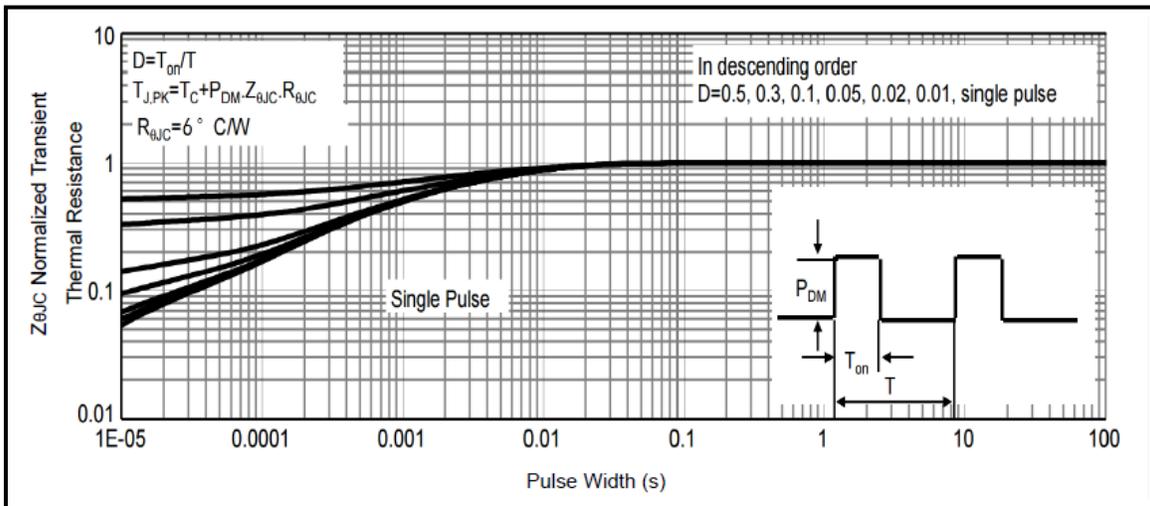
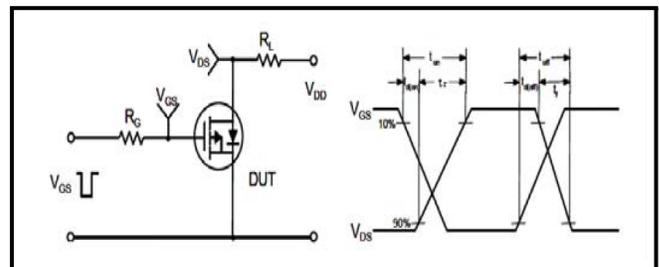
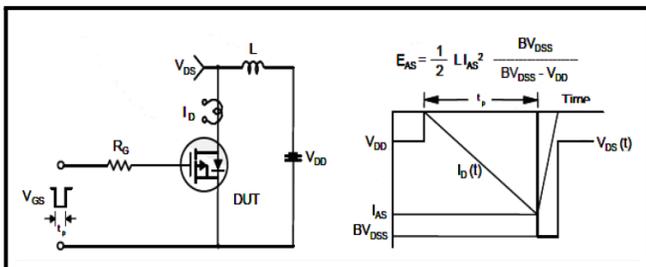


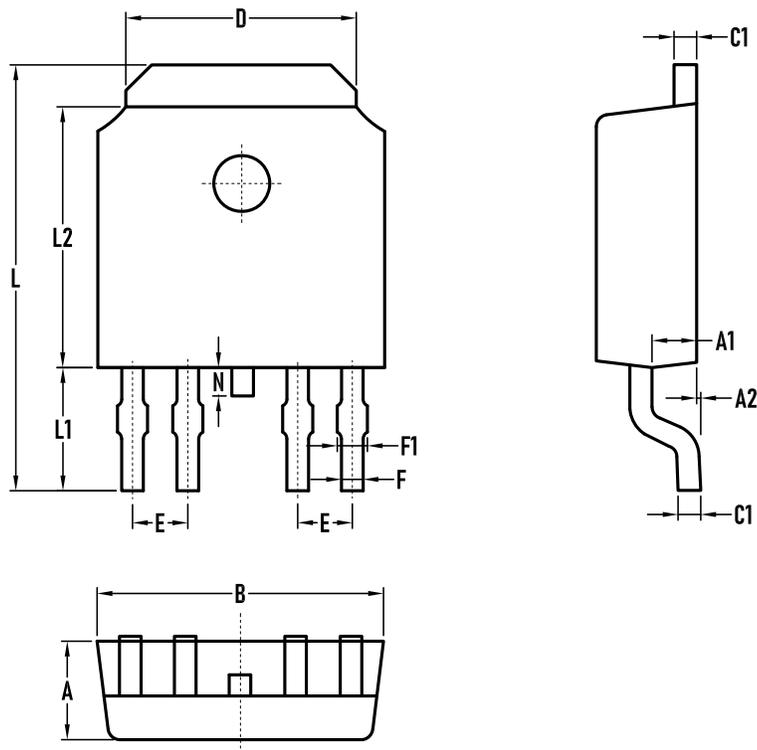
Figure 21: Unclamped Inductive Test Circuit and wave-

Figure 22: Switching Time Test Circuit and waveforms

forms



Packaging Tape - TO-252-4L



SYMBOL	MIN	TYP	MAX
A	2.20	2.30	2.40
A1	0.90	1.00	1.10
A2	0.05	0.15	0.20
B	6.50	6.60	6.70
C	0.46	0.50	0.54
C1	0.46	0.50	0.54
D	5.22	5.32	5.42
E	1.27 typ.		
F	0.40	0.50	0.60
F1	0.50	0.60	0.70
L	9.77	9.97	10.17
L1	2.67	2.87	3.07
L2	6.02	6.10	6.18
N	0.55	0.65	0.75

